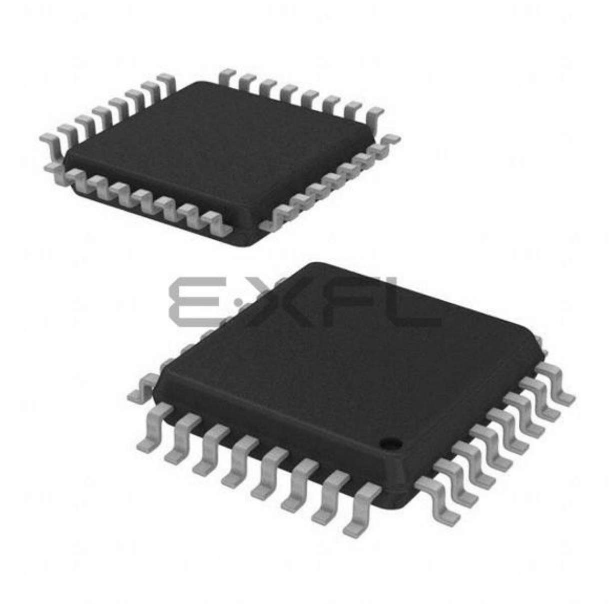


What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	STM8A
Core Size	8-Bit
Speed	16MHz
Connectivity	I²C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	25
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	512 x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 7x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 150°C (TA)
Mounting Type	Surface Mount
Package / Case	32-LQFP
Supplier Device Package	-
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8af6246tdsssy

Contents

5.2 Single wire interface module (SWIM) and debug module (DM)

5.2.1 SWIM

The single wire interface module, SWIM, together with an integrated debug module, permits non-intrusive, real-time in-circuit debugging and fast memory programming. The interface can be activated in all device operation modes and can be connected to a running device (hot plugging).The maximum data transmission speed is 145 bytes/ms.

5.2.2 Debug module

The non-intrusive debugging module features a performance close to a full-flavored emulator. Besides memory and peripheral operation, CPU operation can also be monitored in real-time by means of shadow registers.

- R/W of RAM and peripheral registers in real-time
- R/W for all resources when the application is stopped
- Breakpoints on all program-memory instructions (software breakpoints), except the interrupt vector table
- Two advanced breakpoints and 23 predefined breakpoint configurations

5.3 Interrupt controller

- Nested interrupts with three software priority levels
- 21 interrupt vectors with hardware priority
- Five vectors for external interrupts (up to 34 depending on the package)
- Trap and reset interrupts

5.4 Flash program and data EEPROM

- 16 Kbyte to 32 Kbyte of medium density single voltage program Flash memory
- Up to 1 Kbyte true (not emulated) data EEPROM
- Read while write: writing in the data memory is possible while executing code in the Flash program memory

The whole Flash program memory and data EEPROM are factory programmed with 0x00.

5.4.1 Architecture

- The memory is organized in blocks of 128 bytes each
- Read granularity: 1 word = 4 bytes
- Write/erase granularity: 1 word (4 bytes) or 1 block (128 bytes) in parallel
- Writing, erasing, word and block management is handled automatically by the memory interface.

UART mode

- Full duplex, asynchronous communications - NRZ standard format (mark/space)
- High-precision baud rate generator
  - A common programmable transmit and receive baud rates up to $f_{MASTER}/16$
- Programmable data word length (8 or 9 bits) – 1 or 2 stop bits – parity control
- Separate enable bits for transmitter and receiver
- Error detection flags
- Reduced power consumption mode
- Multi-processor communication - enter mute mode if address match does not occur
- Wakeup from mute mode (by idle line detection or address mark detection)
- Two receiver wakeup modes:
  - Address bit (MSB)
  - Idle line

5.10 Input/output specifications

The product features four different I/O types:

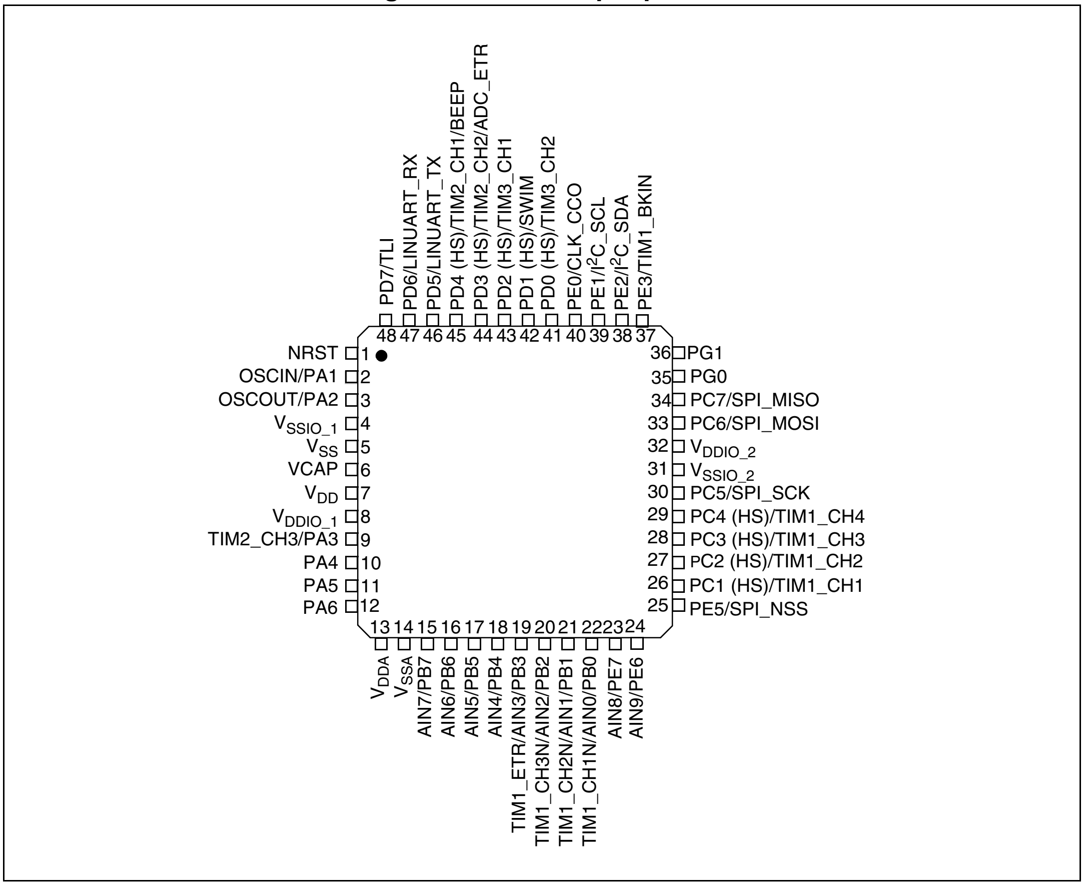
- Standard I/O 2 MHz
- Fast I/O up to 10 MHz
- High sink 8 mA, 2 MHz
- True open drain (I^2C interface)

To decrease EMI (electromagnetic interference), high sink I/Os have a limited maximum slew rate. The rise and fall times are similar to those of standard I/Os.

The analog inputs are equipped with a low leakage analog switch. Additionally, the schmitt-trigger input stage on the analog I/Os can be disabled in order to reduce the device standby consumption.

STM8A I/Os are designed to withstand current injection. For a negative injection current of 4 mA, the resulting leakage current in the adjacent input does not exceed 1 µA. Thanks to this feature, external protection diodes against current injection are no longer required.

Figure 4. LQFP 48-pin pinout



2. (HS) high sink capability.

Table 7. Legend/abbreviation

Type	I= input, O = output, S = power supply	
Level	Input	CM = CMOS (standard for all I/Os)
	Output	HS = High sink (8 mA)
Output speed	O1 = Standard (up to 2 MHz) O2 = Fast (up to 10 MHz) O3 = Fast/slow programmability with slow as default state after reset O4 = Fast/slow programmability with fast as default state after reset	
Port and control configuration	Input	float = floating, wpu = weak pull-up
	Output	T = true open drain, OD = open drain, PP = push pull
Reset state	Bold X (pin state after reset release). Unless otherwise specified, the pin state is the same during the reset phase (i.e. “under reset”) and after internal reset release (i.e. at reset state).	

Table 11. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 50F3	BEEP	BEEP_CSR	BEEP control/status register	0x1F
0x00 50F4 to 0x00 50FF	Reserved area (12 bytes)			
0x00 5200	SPI	SPI_CR1	SPI control register 1	0x00
0x00 5201		SPI_CR2	SPI control register 2	0x00
0x00 5202		SPI_ICR	SPI interrupt control register	0x00
0x00 5203		SPI_SR	SPI status register	0x02
0x00 5204		SPI_DR	SPI data register	0x00
0x00 5205		SPI_CRCPR	SPI CRC polynomial register	0x07
0x00 5206		SPI_RXCRCR	SPI Rx CRC register	0xFF
0x00 5207		SPI_TXCRCR	SPI Tx CRC register	0xFF
0x00 5208 to 0x00 520F	Reserved area (8 bytes)			
0x00 5210	I2C	I2C_CR1	I2C control register 1	0x00
0x00 5211		I2C_CR2	I2C control register 2	0x00
0x00 5212		I2C_FREQR	I2C frequency register	0x00
0x00 5213		I2C_OARL	I2C own address register low	0x00
0x00 5214		I2C_OARH	I2C own address register high	0x00
0x00 5215		Reserved area (1 byte)		
0x00 5216		I2C_DR	I2C data register	0x00
0x00 5217		I2C_SR1	I2C status register 1	0x00
0x00 5218		I2C_SR2	I2C status register 2	0x00
0x00 5219		I2C_SR3	I2C status register 3	0x00
0x00 521A		I2C_ITR	I2C interrupt control register	0x00
0x00 521B		I2C_CCRL	I2C clock control register low	0x00
0x00 521C		I2C_CCRH	I2C clock control register high	0x00
0x00 521D		I2C_TRISER	I2C TRISE register	0x02
0x00 521E to 0x00 523F	Reserved area (24 bytes)			

Table 11. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5314	TIM2	TIM2_CCR3L	TIM2 capture/compare register 3 low	0x00
0x00 5315 to 0x00 531F	Reserved area (11 bytes)			
0x00 5320	TIM3	TIM3_CR1	TIM3 control register 1	0x00
0x00 5321		TIM3_IER	TIM3 interrupt enable register	0x00
0x00 5322		TIM3_SR1	TIM3 status register 1	0x00
0x00 5323		TIM3_SR2	TIM3 status register 2	0x00
0x00 5324		TIM3_EGR	TIM3 event generation register	0x00
0x00 5325		TIM3_CCMR1	TIM3 capture/compare mode register 1	0x00
0x00 5326		TIM3_CCMR2	TIM3 capture/compare mode register 2	0x00
0x00 5327		TIM3_CCER1	TIM3 capture/compare enable register 1	0x00
0x00 5328		TIM3_CNTRH	TIM3 counter high	0x00
0x00 5329		TIM3_CNTRL	TIM3 counter low	0x00
0x00 532A		TIM3_PSCR	TIM3 prescaler register	0x00
0x00 532B		TIM3_ARRH	TIM3 auto-reload register high	0xFF
0x00 532C		TIM3_ARRL	TIM3 auto-reload register low	0xFF
0x00 532D		TIM3_CCR1H	TIM3 capture/compare register 1 high	0x00
0x00 532E		TIM3_CCR1L	TIM3 capture/compare register 1 low	0x00
0x00 532F		TIM3_CCR2H	TIM3 capture/compare register 2 high	0x00
0x00 5330		TIM3_CCR2L	TIM3 capture/compare register 2 low	0x00
0x00 5331 to 0x00 533F	Reserved area (15 bytes)			
0x00 5340	TIM4	TIM4_CR1	TIM4 control register 1	0x00
0x00 5341		TIM4_IER	TIM4 interrupt enable register	0x00
0x00 5342		TIM4_SR	TIM4 status register	0x00
0x00 5343		TIM4_EGR	TIM4 event generation register	0x00
0x00 5344		TIM4_CNTR	TIM4 counter	0x00
0x00 5345		TIM4_PSCR	TIM4 prescaler register	0x00
0x00 5346		TIM4_ARR	TIM4 auto-reload register	0xFF
0x00 5347 to 0x00 53DF	Reserved area (185 bytes)			

Table 11. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 53E0	ADC	ADC _DB0RH	ADC data buffer register 0 high	0x00
0x00 53E1		ADC _DB0RL	ADC data buffer register 0 low	0x00
0x00 53E2		ADC _DB1RH	ADC data buffer register 1 high	0x00
0x00 53E3		ADC _DB1RL	ADC data buffer register 1 low	0x00
0x00 53E4		ADC _DB2RH	ADC data buffer register 2 high	0x00
0x00 53E5		ADC _DB2RL	ADC data buffer register 2 low	0x00
0x00 53E6		ADC _DB3RH	ADC data buffer register 3 high	0x00
0x00 53E7		ADC _DB3RL	ADC data buffer register 3 low	0x00
0x00 53E8		ADC _DB4RH	ADC data buffer register 4 high	0x00
0x00 53E9		ADC _DB4RL	ADC data buffer register 4 low	0x00
0x00 53EA		ADC _DB5RH	ADC data buffer register 5 high	0x00
0x00 53EB		ADC _DB5RL	ADC data buffer register 5 low	0x00
0x00 53EC		ADC _DB6RH	ADC data buffer register 6 high	0x00
0x00 53ED		ADC _DB6RL	ADC data buffer register 6 low	0x00
0x00 53EE		ADC _DB7RH	ADC data buffer register 7 high	0x00
0x00 53EF		ADC _DB7RL	ADC data buffer register 7 low	0x00
0x00 53F0		ADC _DB8RH	ADC data buffer register 8 high	0x00
0x00 53F1		ADC _DB8RL	ADC data buffer register 8 low	0x00
0x00 53F2		ADC _DB9RH	ADC data buffer register 9 high	0x00
0x00 53F3		ADC _DB9RL	ADC data buffer register 9 low	0x00
0x00 53F4 to 0x00 53FF	Reserved area (12 bytes)			
0x00 5400	ADC	ADC _CSR	ADC control/status register	0x00
0x00 5401		ADC_CR1	ADC configuration register 1	0x00
0x00 5402		ADC_CR2	ADC configuration register 2	0x00
0x00 5403		ADC_CR3	ADC configuration register 3	0x00
0x00 5404		ADC_DRH	ADC data register high	0xXX
0x00 5405		ADC_DRL	ADC data register low	0xXX
0x00 5406		ADC_TDRH	ADC Schmitt trigger disable register high	0x00
0x00 5407		ADC_TDRL	ADC Schmitt trigger disable register low	0x00
0x00 5408		ADC _HTRH	ADC high threshold register high	0xFF
0x00 5409		ADC_HTRL	ADC high threshold register low	0x03
0x00 540A		ADC _LTRH	ADC low threshold register high	0x00

Table 15. Option bytes (continued)

Addr.	Option name	Option byte no.	Option bits 7	6	5	4	3	2	1	0	Factory default setting
0x00 480B	TMU	OPT6	TMU[3:0]								0x00
0x00 480C		NOPT6	NTMU[3:0]								0xFF
0x00 480D	Flash wait states	OPT7	Reserved							WAIT STATE	0x00
0x00 480E		NOPT7	Reserved							NWAIT STATE	0xFF
0x00 480F	Reserved										
0x00 4810	TMU	OPT8	TMU_KEY 1 [7:0]								0x00
0x00 4811		OPT9	TMU_KEY 2 [7:0]								0x00
0x00 4812		OPT10	TMU_KEY 3 [7:0]								0x00
0x00 4813		OPT11	TMU_KEY 4 [7:0]								0x00
0x00 4814		OPT12	TMU_KEY 5 [7:0]								0x00
0x00 4815		OPT13	TMU_KEY 6 [7:0]								0x00
0x00 4816		OPT14	TMU_KEY 7 [7:0]								0x00
0x00 4817		OPT15	TMU_KEY 8 [7:0]								0x00
0x00 4818		OPT16	TMU_MAXATT [7:0]								0xC7
0x00 4819 to 487D	Reserved										
0x00 487E	Boot-loader(1)	OPT17	BL [7:0]								0x00
0x00 487F		NOPT17	NBL[7:0]								0xFF

1. This option consists of two bytes that must have a complementary value in order to be valid. If the option is invalid, it has no effect on EMC reset.

Table 22. Operating conditions at power-up/power-down

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
t_{VDD}	V_{DD} rise time rate	-	2(1)	-	∞	µs/V
	V_{DD} fall time rate	-	2(1)	-	∞	
t_{TEMP}	Reset release delay	V_{DD} rising	-	1	1.7	ms
	Reset generation delay	V_{DD} falling	-	3	-	µs
V_{IT+}	Power-on reset threshold(2) (3)	-	2.65	2.8	2.95	V
V_{IT-}	Brown-out reset threshold	-	2.58	2.73	2.88	
$V_{HYS(BOR)}$	Brown-out reset hysteresis	-	-	70(1)	-	mV

1. Guaranteed by design, not tested in production
2. If V_{DD} is below 3 V, the code execution is guaranteed above the V_{IT-} and V_{IT+} thresholds. RAM content is kept. The EEPROM programming sequence must not be initiated.
3. There is inrush current into V_{DD} present after device power on to charge C_{EXT} capacitor. This inrush energy depends from C_{EXT} capacitor value. For example, a C_{EXT} of 1µF requires Q=1 µF x 1.8V = 1.8 µC.

Table 26. Programming current consumption

Symbol	Parameter	Conditions	Typ	Max	Unit
$I_{DD(PROG)}$	Programming current	V_{DD} = 5 V, -40 °C to 150 °C, erasing and programming data or Flash program memory	1.0	1.7	mA

Table 27. Typical peripheral current consumption V_{DD} = 5.0 V(1)

Symbol	Parameter	Typ. f_{master} = 2 MHz	Typ. f_{master} = 16 MHz	Unit
$I_{DD(TIM1)}$	TIM1 supply current(2)	0.03	0.23	mA
$I_{DD(TIM2)}$	TIM2 supply current (2)	0.02	0.12	
$I_{DD(TIM3)}$	TIM3 supply current(2)	0.01	0.1	
$I_{DD(TIM4)}$	TIM4 supply current(2)	0.004	0.03	
$I_{DD(LINUART)}$	LINUART supply current(2)	0.03	0.11	
$I_{DD(SPI)}$	SPI supply current(2)	0.01	0.04	
$I_{DD(I^2C)}$	I^2C supply current(2)	0.02	0.06	
$I_{DD(AWU)}$	AWU supply current(2)	0.003	0.02	
$I_{DD(TOT\_DIG)}$	All digital peripherals on	0.22	1	
$I_{DD(ADC)}$	ADC supply current when converting(3)	0.93	0.95	

1. Typical values not tested in production. Since the peripherals are powered by an internally regulated, constant digital supply voltage, the values are similar in the full supply voltage range.
2. Data based on a differential I_{DD} measurement between no peripheral clocked and a single active peripheral. This measurement does not include the pad toggling consumption.
3. Data based on a differential I_{DD} measurement between reset configuration and continuous A/D conversions.

Current consumption curves

Figure 10 to *Figure 15* show typical current consumption measured with code executing in RAM.

Figure 10. Typ. $I_{DD(RUN)HSE}$ vs. V_{DD} @f_{CPU} = 16 MHz, peripheral = on

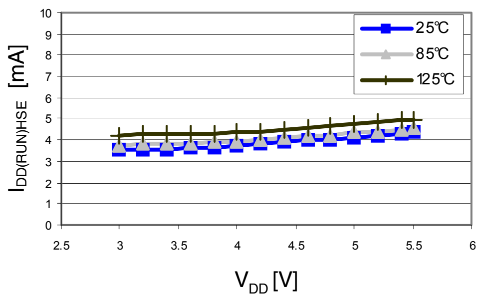


Figure 11. Typ. $I_{DD(RUN)HSE}$ vs. f_{CPU} @ V_{DD} = 5.0 V, peripheral = on

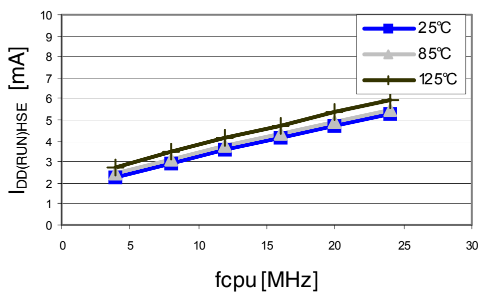


Figure 12. Typ. $I_{DD(RUN)HSI}$ vs. V_{DD} @ f_{CPU} = 16 MHz, peripheral = off

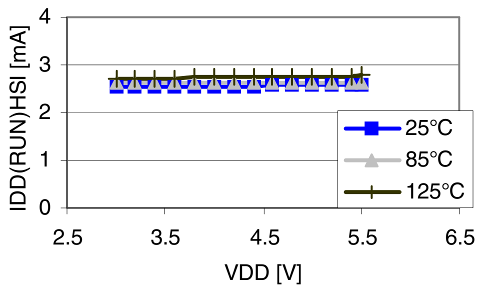


Figure 13. Typ. $I_{DD(WFI)HSE}$ vs. V_{DD} @ f_{CPU} = 16 MHz, peripheral = on

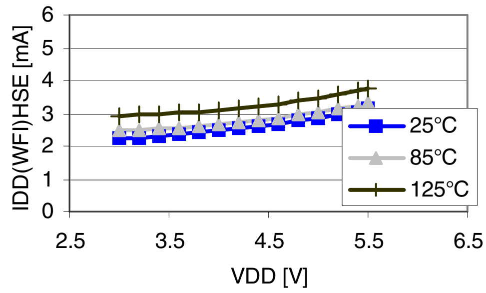


Figure 14. Typ. $I_{DD(WFI)HSE}$ vs. f_{CPU} @ V_{DD} = 5.0 V, peripheral = on

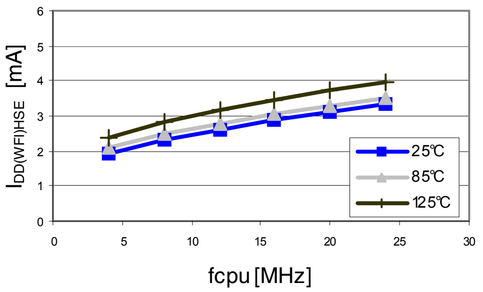
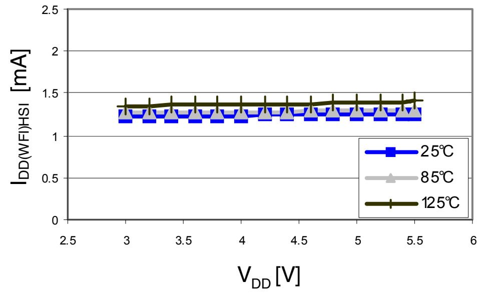


Figure 15. Typ. $I_{DD(WFI)HSI}$ vs. V_{DD} @ f_{CPU} = 16 MHz, peripheral = off



10.3.3 External clock sources and timing characteristics

HSE user external clock

Subject to general operating conditions for V_{DD} and T_A.

Table 28. HSE user external clock characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSE_ext}	User external clock source frequency	T_A is -40 to 150 °C	0(1)	-	16	MHz
V_{HSEdHL}	Comparator hysteresis	-	0.1 x V_{DD}	-	-	V
V_{HSEH}	OSCIN input pin high level voltage	-	0.7 x V_{DD}	-	V_{DD}	
V_{HSEL}	OSCIN input pin low level voltage	-	V_{SS}	-	0.3 x V_{DD}	
I_{LEAK_HSE}	OSCIN input leakage current	$V_{SS} < V_{IN} < V_{DD}$	-1	-	+1	µA

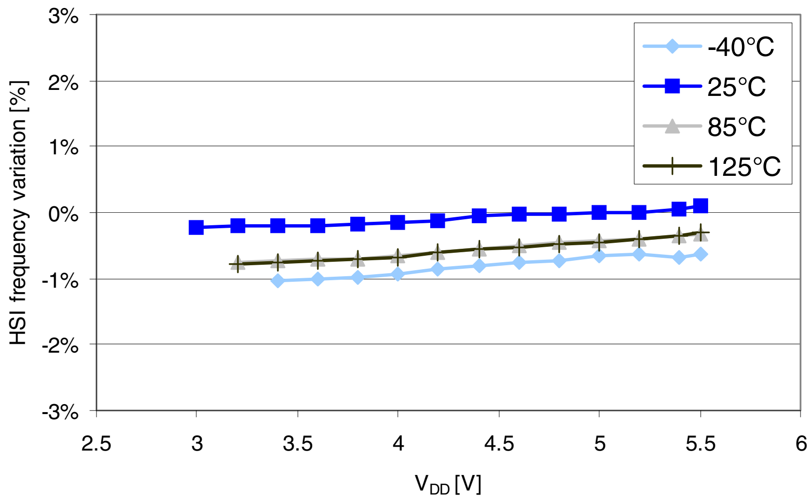
1. In CSS is used, the external clock must have a frequency above 500 kHz.

Table 30. HSI oscillator characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
ACC_{HS}	HSI oscillator user trimming accuracy	Trimmed by the application for any V_{DD} and T_A conditions	-1(1)	-	1(1)	%
			-0.5(1)	-	0.5(1)	
	HSI oscillator accuracy (factory calibrated)	$3.0\ V \leq V_{DD} \leq 5.5\ V$, $-40\ °C \leq T_A \leq 150\ °C$	-5	-	5	
		$3.0V \leq V_{DD} \leq 5.5V$, $-40°C \leq T_A \leq 125\ °C$	-2.5(2)	-	2.5(2)	
$t_{su(HSI)}$	HSI oscillator wakeup time	-	-	-	2(3)	µs

1. Depending on option byte setting (OPT3 and NOPT3)
2. These values are guaranteed for STM8AF62x6ITx order codes only.
3. Guaranteed by characterization, not tested in production

Figure 18. Typical HSI frequency vs V_{DD}



Low speed internal RC oscillator (LSI)

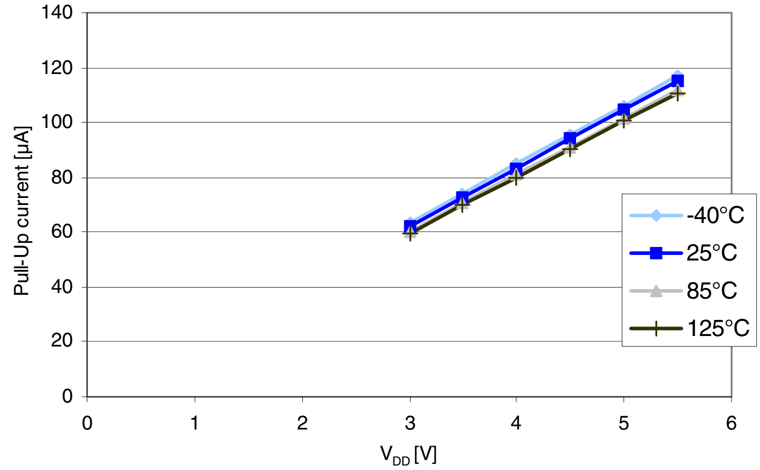
Subject to general operating conditions for V_{DD} and T_A.

Table 31. LSI oscillator characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{LSI}	Frequency	-	112	128	144	kHz
$t_{su(LSI)}$	LSI oscillator wakeup time	-	-	-	7(1)	µs

1. Data based on characterization results, not tested in production.

Figure 22. Typical pull-up current I_{pu} vs V_{DD} @ four temperatures



Note: The pull-up is a pure resistor (slope goes through 0).

Typical output level curves

Figure 23 to *Figure 32* show typical output level curves measured with output on a single pin.

Figure 23. Typ. V_{OL} @ V_{DD} = 3.3 V (standard ports)

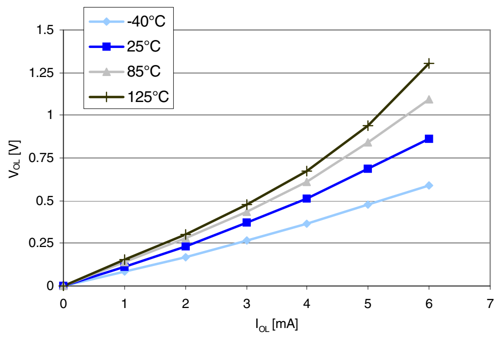


Figure 24. Typ. V_{OL} @ V_{DD} = 5.0 V (standard ports)

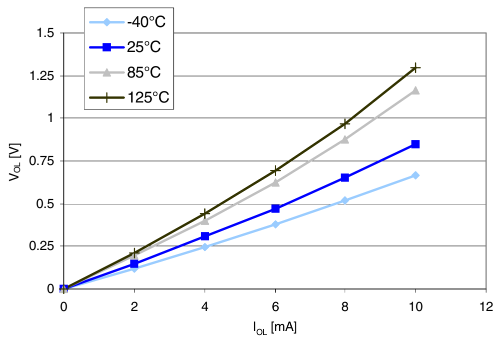


Figure 25. Typ. V_{OL} @ V_{DD} = 3.3 V (true open drain ports)

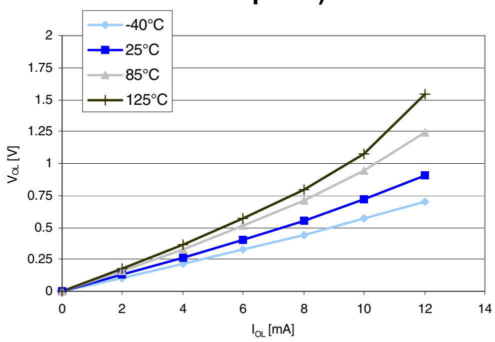
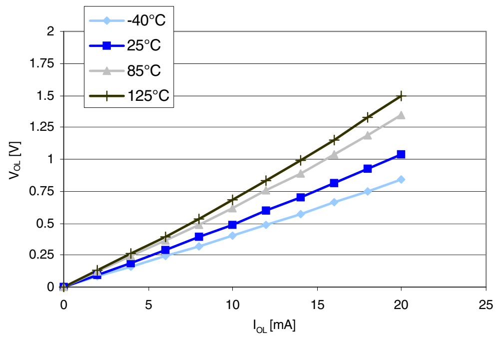
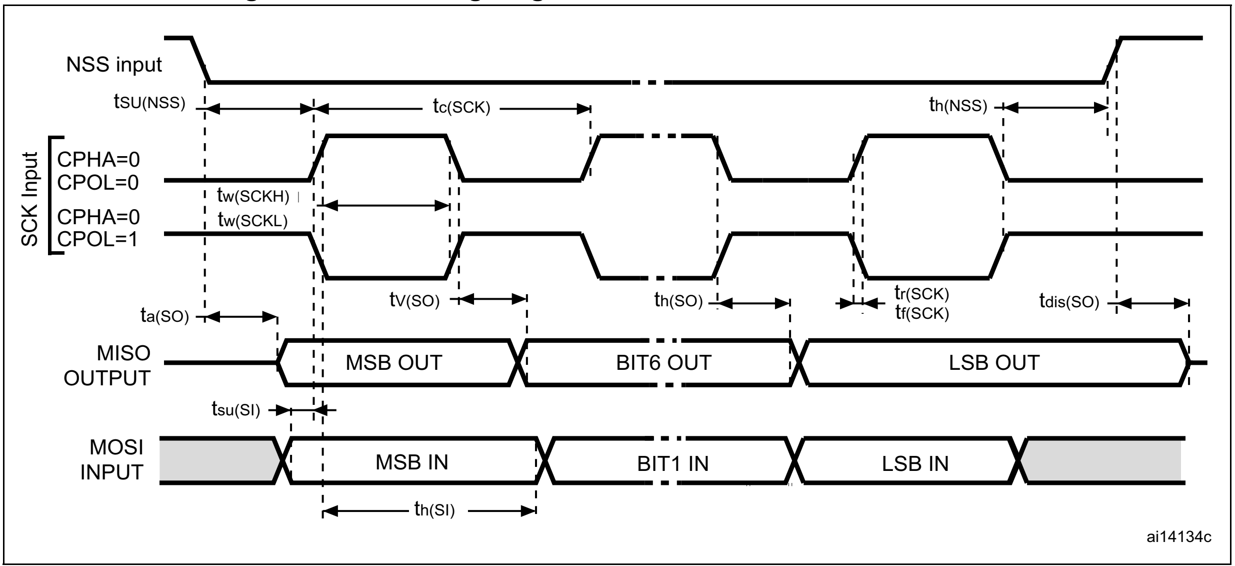


Figure 26. Typ. V_{OL} @ V_{DD} = 5.0 V (true open drain ports)



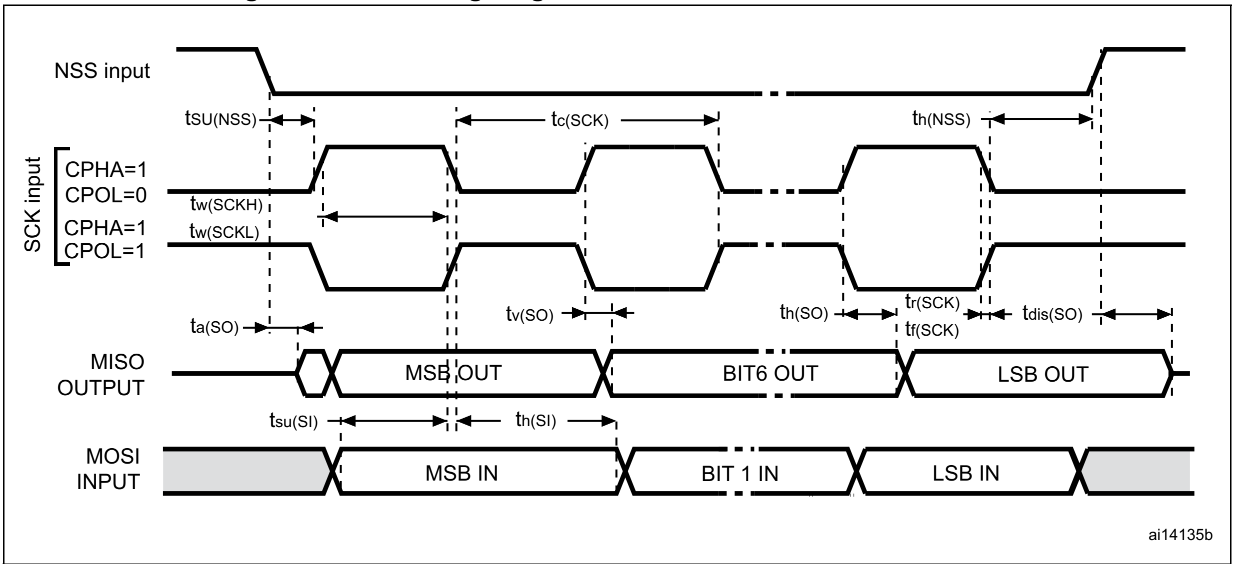
3. Values based on design simulation and/or characterization results, and not tested in production.
4. Min time is for the minimum time to drive the output and the max time is for the maximum time to validate the data.
5. Min time is for the minimum time to invalidate the output and the max time is for the maximum time to put the data in Hi-Z.

Figure 37. SPI timing diagram where slave mode and CPHA = 0



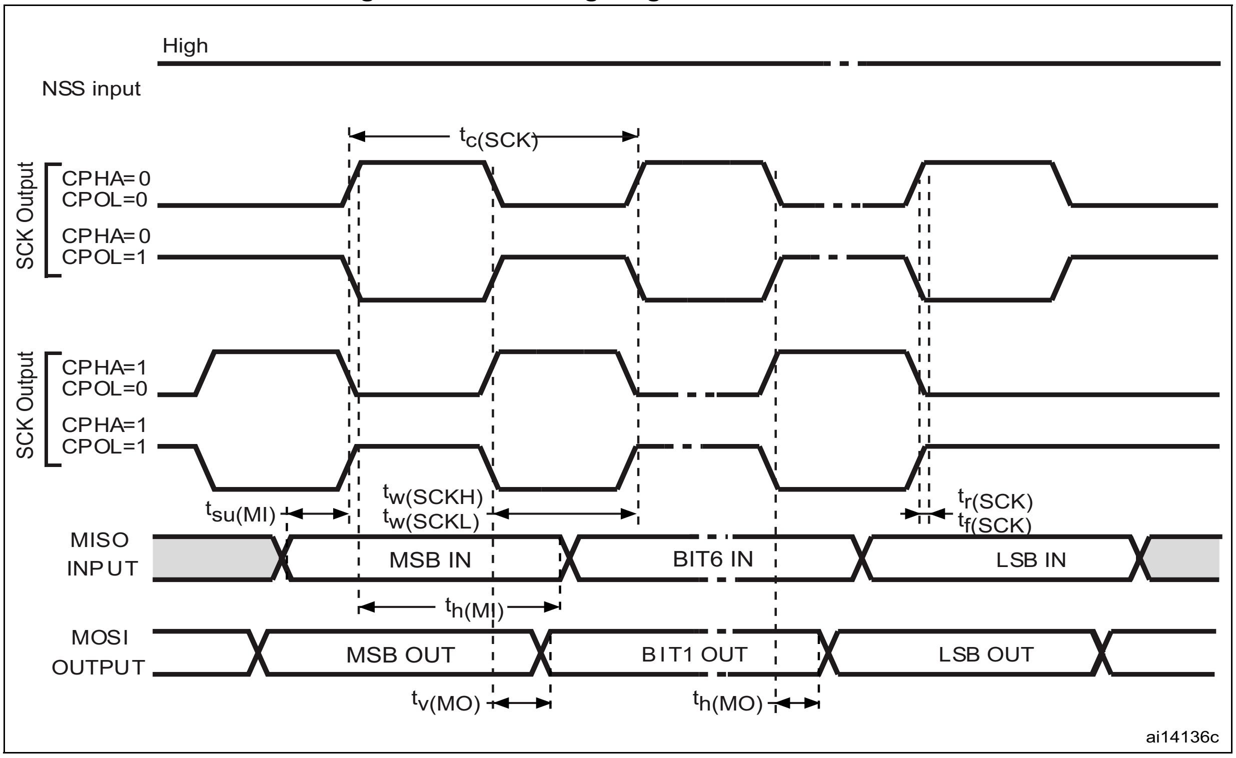
1. Measurement points are at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD}.

Figure 38. SPI timing diagram where slave mode and CPHA = 1



1. Measurement points are at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD}.

Figure 39. SPI timing diagram - master mode



1. Measurement points are at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD}.

Static latch-up

Two complementary static tests are required on 10 parts to assess the latch-up performance.

- A supply overvoltage (applied to each power supply pin) and
- A current injection (applied to each input, output and configurable I/O pin) are performed on each sample.

This test conforms to the EIA/JESD 78 IC latch-up standard. For more details, refer to the application note AN1181.

Table 45. Electrical sensitivities

Symbol	Parameter	Conditions	Class(1)
LU	Static latch-up class	$T_A = 25\ °C$	A
		$T_A = 85\ °C$	
		$T_A = 125\ °C$	
		$T_A = 150\ °C$	

1. Class description: A Class is an STMicroelectronics internal specification. All its limits are higher than the JEDEC specifications, that means when a device belongs to class A it exceeds the JEDEC standard. B class strictly covers all the JEDEC criteria (international standard).

Table 47. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package mechanical data

Symbol	millimeters			inches(1)		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	8.800	9.000	9.200	0.3465	0.3543	0.3622
D1	6.800	7.000	7.200	0.2677	0.2756	0.2835
D3	-	5.500	-	-	0.2165	-
E	8.800	9.000	9.200	0.3465	0.3543	0.3622
E1	6.800	7.000	7.200	0.2677	0.2756	0.2835
E3	-	5.500	-	-	0.2165	-
e	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	3.5°	7°	0°	3.5°	7°
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

12 Ordering information

Figure 51. STM8AF6246/48/66/68 ordering information scheme(1) (2)

Example: STM8A F 62 6 6 I T D xxx(3) Y

Product class
8-bit automotive microcontroller

Program memory type
F = Flash + EEPROM
P = FASTROM

Device family
62 = Silicon rev X and rev W, LIN only

Program memory size
4 = 16 Kbyte
6 = 32 Kbyte

Pin count
6 = 32 pins
8 = 48 pins

HSI accuracy
Blank = ± 5 %
I = ± 2.5 %

Package type
T = LQFP
U = VFQFPN

Temperature range
A = -40 to 85 °C
C = -40 to 125 °C
D = -40 to 150 °C

Packing
Y = Tray
U = Tube
X = Tape and reel compliant with EIA 481-C

1. For a list of available options (e.g. memory size, package) and orderable part numbers or for further information on any aspect of this device, please go to *www.st.com* or contact the nearest ST Sales Office.
2. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.
3. Customer specific FASTROM code or custom device configuration. This field shows ‘SSS’ if the device contains a super set silicon, usually equipped with bigger memory and more I/Os. This silicon is supposed to be replaced later by the target silicon.

13 STM8 development tools

Development tools for the STM8A microcontrollers include the
- STice emulation system offering tracing and code profiling
- STVD high-level language debugger including assembler and visual development environment - seamless integration of third party C compilers.
- STVP Flash programming software

In addition, the STM8A comes with starter kits, evaluation boards and low-cost in-circuit debugging/programming tools.

13.1 Emulation and in-circuit debugging tools

The STM8 tool line includes the STice emulation system offering a complete range of emulation and in-circuit debugging features on a platform that is designed for versatility and cost-effectiveness. In addition, STM8A application development is supported by a low-cost in-circuit debugger/programmer.

The STice is the fourth generation of full-featured emulators from STMicroelectronics. It offers new advanced debugging capabilities including tracing, profiling and code coverage analysis to help detect execution bottlenecks and dead code.

In addition, STice offers in-circuit debugging and programming of STM8A microcontrollers via the STM8 single wire interface module (SWIM), which allows non-intrusive debugging of an application while it runs on the target microcontroller.

For improved cost effectiveness, STice is based on a modular design that allows users to order exactly what they need to meet their development requirements and to adapt their emulation system to support existing and future ST microcontrollers.

13.1.1 STice key features

- Program and data trace recording up to 128 K records
- Advanced breakpoints with up to 4 levels of conditions
- Data breakpoints
- Real-time read/write of all device resources during emulation
- Occurrence and time profiling and code coverage analysis (new features)
- In-circuit debugging/programming via SWIM protocol
- 8-bit probe analyzer
- 1 input and 2 output triggers
- USB 2.0 high speed interface to host PC
- Power supply follower managing application voltages between 1.62 to 5.5 V
- Modularity that allows users to specify the components they need to meet their development requirements and adapt to future requirements.
- Supported by free software tools that include integrated development environment (IDE), programming software interface and assembler for STM8.

Table 50. Document revision history (continued)

Date	Revision	Changes
09-Jun-2015	10	Updated: – the product naming in the document headers and captions, – LIN version in *Features* and *Section 5.9.3: Universal asynchronous receiver/transmitter with LIN support (LINUART)*. Added: – the third table footnote to *Table 22: Operating conditions at power-up/power-down*, – *Figure 44: VFQFPN32 marking example (package top view)*, – *Figure 47: LQFP48 marking example (package top view)*, – *Figure 50: LQFP32 marking example (package top view)*, – the note about the parts marked “E” and “ES” below *Figure 51: STM8AF6246/48/66/68 ordering information scheme(1) (2)*, – the standard for EMI characteristics in *Table 43: EMI data*. Removed the references to STM8AF61xx and STM8AH61xx obsolete products. Moved *Section 11.4: Thermal characteristics* to *Section 11: Package information*.
14-Jun-2016	11	Update *Table 46: VFQFPN32 - 32-pin, 5x5 mm, 0.5 mm pitch very thin profile fine pitch quad flat package mechanical data*